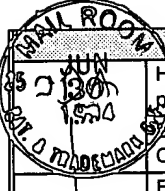
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				APPLICANT Jonathan S. NIMITZ et al			
				FILING DATE June 30, 1994		GROUP	
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EXAMINER <i>Joseph D. Anderson</i>	DATE CONSIDERED <i>10/28/94</i>

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.